



#### **Features**

- 150V/200A  $R_{DS (ON)} = 6.3 \text{m}\Omega(\text{Typ.})@V_{GS} = 10V$
- Advanced HEFE <sup>®</sup> Technology
   Ultra Low On-Resistanc
- $\bullet \ \ \, \mathsf{Excellent} \quad {}_{g}\mathsf{xR}_{\mathsf{DS}(\mathsf{on})}\mathsf{Product}$
- 100% avalanche testedh t t d
- 175°C Operating Temperatur
- · Lead Free and Green Devices Available (RoHS Compliant

## **Applications**

- Motor Drive
- Uninterruptible Power Supplie
- DC/DC converte
- General Purpose Application

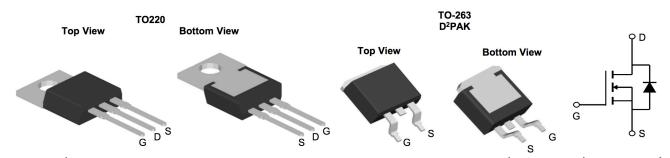






Halogen-Free

#### **Pin Configurations**



#### **Common Ratings** (T<sub>C</sub>=25°C Unless Otherwise Noted)

V °C 5 °C A							
°C 5 °C							
5 °C							
_							
Α							
А							
A							
10/							
- W							
°C/W							
°C/W							
Drain-Source Avalanche Ratings							
mJ							



## **Electrical Characteristics** (T<sub>C</sub>=25°C Unless Otherwise Noted)

Symbol	Davamatav	Tool Co	F	l lnit			
Symbol	Parameter	Test Condition		Min.	Тур.	Max.	Unit
Static Cha	racteristics						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>DS</sub> =2	50μA	150			V
	Zero Gate Voltage Drain Current	$V_{DS}$ =150V, $V_{GS}$	s=0V			1	^
I <sub>DSS</sub>	Zero Gale Vollage Drain Current		T <sub>J</sub> =125°C			30	μΑ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS}=V_{GS}$ , $I_{DS}=2$	.50μA	2.5		4.5	V
I <sub>GSS</sub>	Gate Leakage Current	$V_{GS}$ =±25V, $V_{DS}$	3=0V			±100	nA
R <sub>DS(ON)</sub>	Drain-Source On-state Resistance	V <sub>GS</sub> =10V, I <sub>DS</sub> =	75A		6.3	7.3	mΩ
	racteristics						
V <sub>SD</sub>	Diode Forward Voltage	I <sub>SD</sub> =75A, V <sub>GS</sub> =0	)V			1.2	V
trr	Reverse Recovery Time	175 A dl/a		55		ns	
Qrr	Reverse Recovery Charge	Isp=75A, dlsp/d		105		nC	
Dynamic C	Characteristics (5)						
$R_G$	Gate Resistance	V <sub>GS</sub> =0V,V <sub>DS</sub> =0V,F=1MHz			1.5		Ω
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =50V, Frequency=1.0MHz			5140		
C <sub>oss</sub>	Output Capacitance				409		pF
C <sub>rss</sub>	Reverse Transfer Capacitance	-i requerioy- i.e		10			
t <sub>d(ON)</sub>	Turn-on Delay Time				37		
t <sub>r</sub>	Turn-on Rise Time	V <sub>DD</sub> =75V,I <sub>DS</sub> =7	5A,		123		
t <sub>d(OFF)</sub>	Turn-off Delay Time	$V_{GEN}$ =10V, $R_{G}$ =25 $\Omega$			190		ns
t <sub>f</sub>	Turn-off Fall Time			67			
Gate Char	ge Characteristics <sup>⑤</sup>	•		•			
Q <sub>g</sub>	Total Gate Charge				247		
$Q_{gs}$	Gate-Source Charge	V <sub>DS</sub> =120V, V <sub>GS</sub> I <sub>DS</sub> =75A	<sub>s</sub> =10V,		19		nC
$Q_{gd}$	Gate-Drain Charge	יטס י סיי		168			

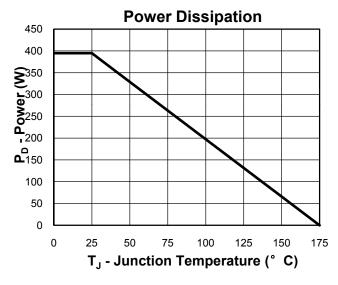
Notes:

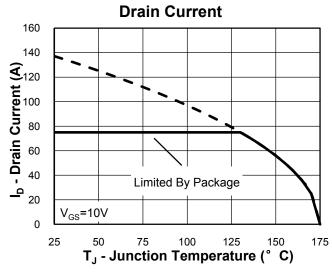
- ①Pulse width limited by safe operating area.
- ②Calculated continuous current based on maximum allowable junction temperature. The package limitation current is 75A.
- $\$ 3Limited by T<sub>Jmax</sub>, I<sub>AS</sub> =53A, V<sub>DD</sub> = 48V, R<sub>G</sub> = 47Ω , Starting T<sub>J</sub> = 25°C.
- ⊕Pulse test;Pulse width≤300µs, duty cycle≤2%.
- ⑤Guaranteed by design, not subject to production testing.

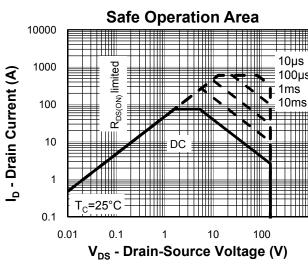
Device	Marking	Package	Packaging	Quantity	Reel Size	Tape width
XPX150N200TU	XPX150N200TU	TO263	Tube	50	-	-

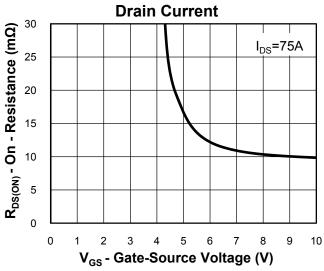


## **Typical Characteristics**

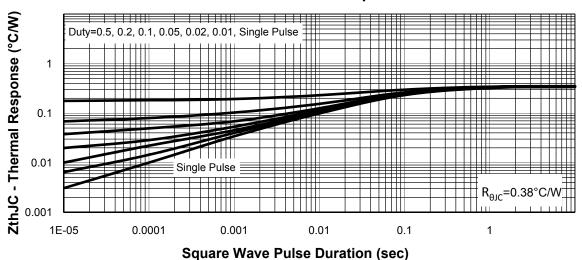






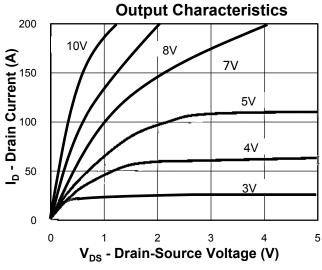


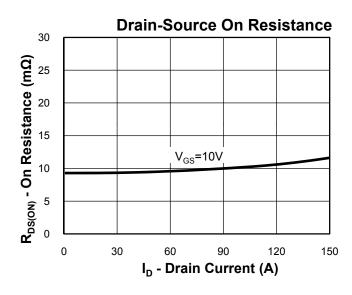
#### **Thermal Transient Impedance**

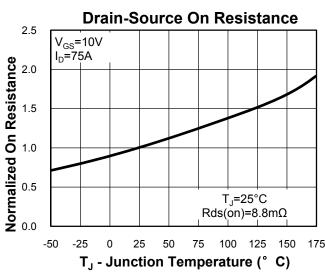


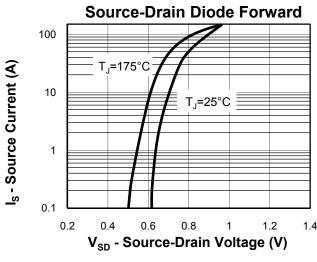


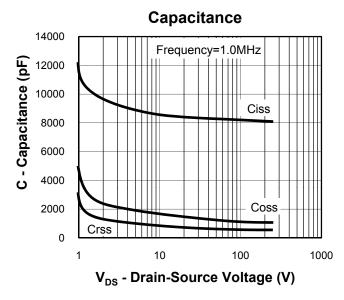
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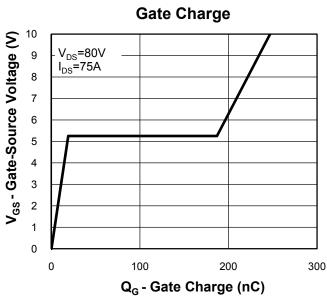






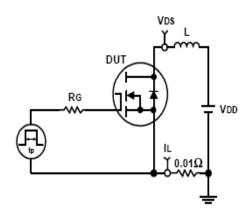


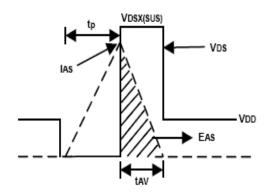




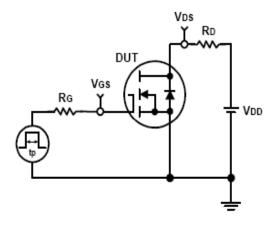


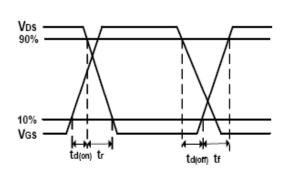
## **Avalanche Test Circuit and Waveforms**





## **Switching Time Test Circuit and Waveforms**

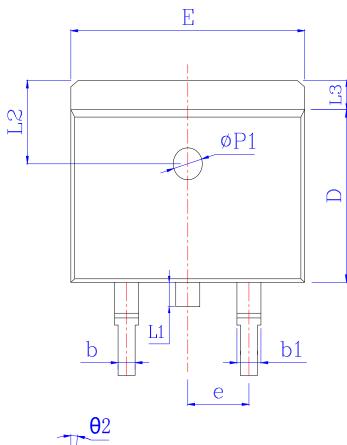


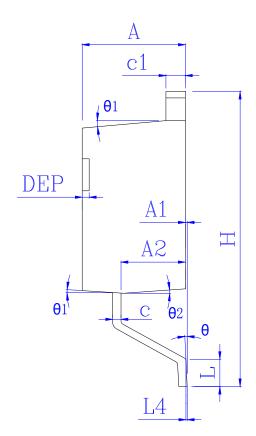


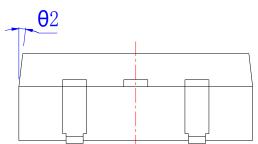


# **Package Information**

# TO263





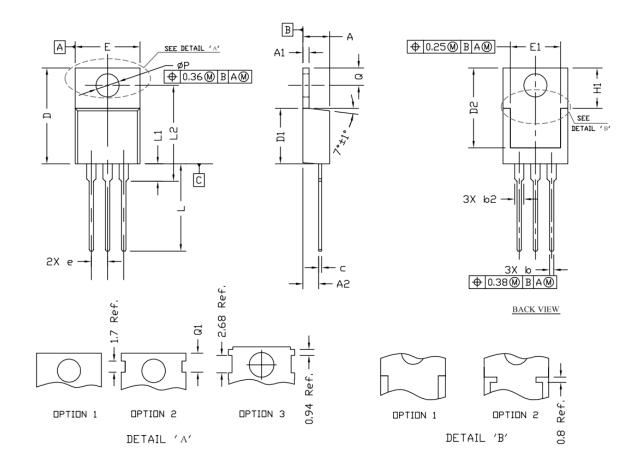


SYMBOL	MM			INCH			SYMBOL		MM			INCH	
OTHDOL	MIN	NOM	MAX	MIN	NOM	MAX		MIN	NOM	MAX	MIN	NOM	MAX
A	4.40	4.55	4.72	0.173	0.179	0.186	L	1.94	2.30	2.60	0.076	0.091	0.102
A1	0.00	0.10	0.25	0.000	0.005	0.010	L3	1.17	1.29	1.40	0.046	0.051	0.055
A2	2.59	2.69	2.79	0.102	0.106	0.110	L1	*	*	1.70	*	*	0.067
b	0.76	*	0.90	0.030	*	0.035	L4		0.25 BSC			0.01 BSC	
b1	1.22	*	1.36	0.048	*	0.054	L2		2.50 REF			0.098 REF	7
С	0.33	*	0.47	0.013	*	0.019	θ	0°	*	8°	0°	*	8°
c1	1.22	*	1.32	0.048	*	0.052	θ1	5°	7°	9°	5°	7°	9°
D	8.60	*	9. 29	0.339	*	0.366	θ2	1°	3°	5°	1°	3°	5°
Е	9.95	*	10.26	0.392	*	0.404	DEP	0.05	0.10	0. 20	0.002	0.004	0.008
е		2.54BSC	64BSC 0. 100BSC		Фр1	1.40	1.50	1.60	0.055	0.059	0.063		
Н	14.70	15. 10	15. 79	0.579	0. 594	0.622							

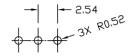


#### **Package Information**

#### TO220 PACKAGE OUTLINE



#### RECOMMENDATION OF HOLE PATTERN



UNIT: mm

- NOTE
  1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.
  MOLD FLASH SHOULD BE LESS THAN 6 MIL.
  2. TOLERANCE 0.100 MILLIMETERS UNLESS OTHERWISE SPECIFIED.

- 2. TOERGALE OF THE WAS CALLED OF THE WAS ESTABLED AS CONTROLLING DIMENSION IS MILLIMETER.

  CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.

SYMBOLS	DIMENS	IONS IN MILI	LIMETERS	DIME	II NI ZNDIZN	NCHES
31MBULS	MIN	NDM	MAX	MIN	NDM	MAX
Α	4,30	4,45	4.72	0.169	0,175	0.186
A1	1.15	1.27	1.40	0.045	0.050	0.055
A2	2.20	2.67	2.90	0.087	0,105	0.114
b	0.69	0.81	0.95	0.027	0.032	0.037
b2	1.17	1.37	1.45	0.046	0.050	0.068
С	0.36	0.38	0.60	0.014	0.015	0.024
D	14.50	15.44	15.80	0.571	0.608	0.622
D1	8.59	9.14	9.65	0,338	0.360	0.380
D2	11.43	11.73	12.48	0.450	0.462	0.491
е		2.54 BS0			0.100 BSC	,
Ε	9.66	10.03	10.54	0.380	0,395	0,415
E1	6.22			0.245		
H1	6.10	6.30	6.50	0.240	0.248	0.256
L	12.27	12.82	14.27	0.483	0.505	0.562
L1	2.47		3.90	0.097		0.154
L2			16.70			0.657
Q	2.59	2.74	2.89	0.102	0.108	0.114
ØΡ	3.50	3.84	3,89	0.138	0.151	0.153
Q1	2,70		2,90	0,106		0.114



#### Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time		
Pb device	245℃±5℃	5sec±1sec		
Pb-Free device	260℃+0/-5℃	5sec±1sec		



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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